Image Processing for Physicists

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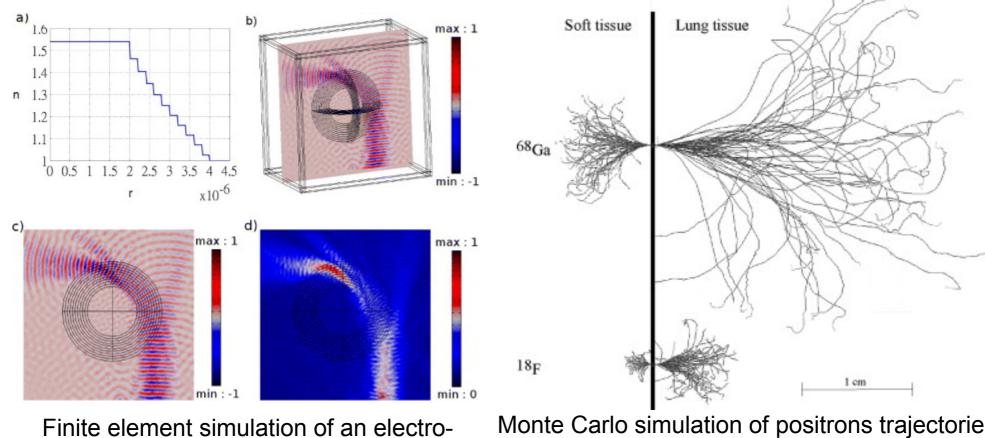
Wave propagation and imaging with lenses

Overview

- Propagation modelization
- Wave propagation:
 - [–] Near-field regime
 - [–] Far-field regime

• Motivations:

1. Validation



inite element simulation of an electromagnetic field in a dielectric Monte Carlo simulation of positrons trajectories resulting from ⁶⁸Ga and ¹⁸F decay.

sources: T.M. Chang *et al.* New J. Phys. (2012) A. Sanchez-Crespo, Appl. Rad. Isotopes (2012)

• Motivations:

2. Inversion



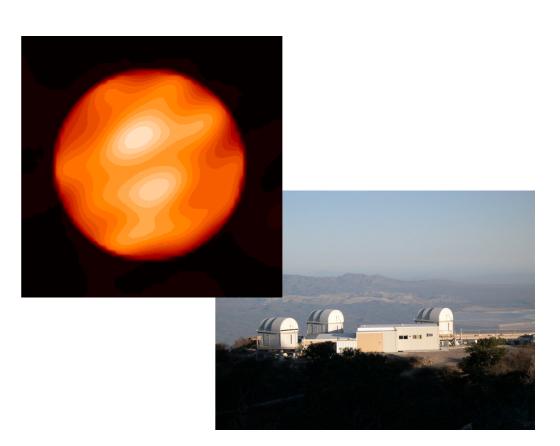


Image reconstruction from sound wave propagation (ultrasonography)

The surface of Betelgeuse reconstructed from interferometric data (IOTA)

sources: wikipedia Haubois *et al. Astronom. & Astrophys.* (2009)

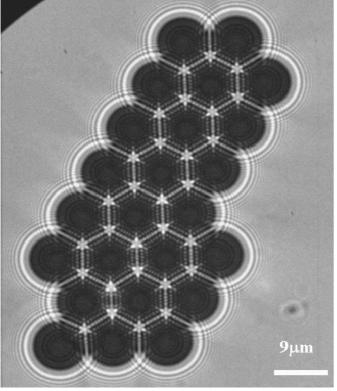
- Particles
 - Model particle tracks (rays) through different media
 - Model may include: refraction, force fields, particle decay and interactions
 - Not included: diffraction

- Wave
 - Model the interaction of a field with a medium
 - ^ Can be very complicated \rightarrow approximations are needed

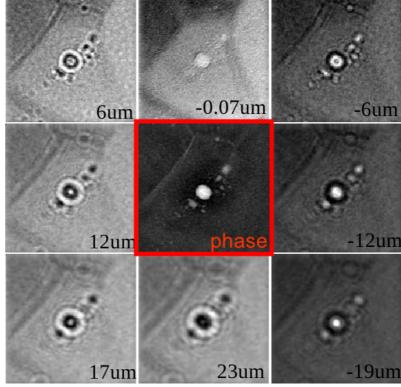
Starting point: Helmholtz equation

- for EM field: neglect polarization (scalar wave approximation)
- Maxwell eq. $\gamma = 0^{2} \gamma + \frac{n^{2}}{c^{2}} \frac{\partial^{2}}{\partial \tau^{2}} \gamma = 0$ for electron wave, assume high energy electrons V: complex-valued sealar field n: index of refraction $Y = Y_{e} e$ with $k^{2} = n^{2} w^{2}$ c: speed of light constant n: plane wave solutions Wave propagation

- Useful to:
 - better understand optical systems
 - understand diffraction, holography, phase contrast, interferometry, ...

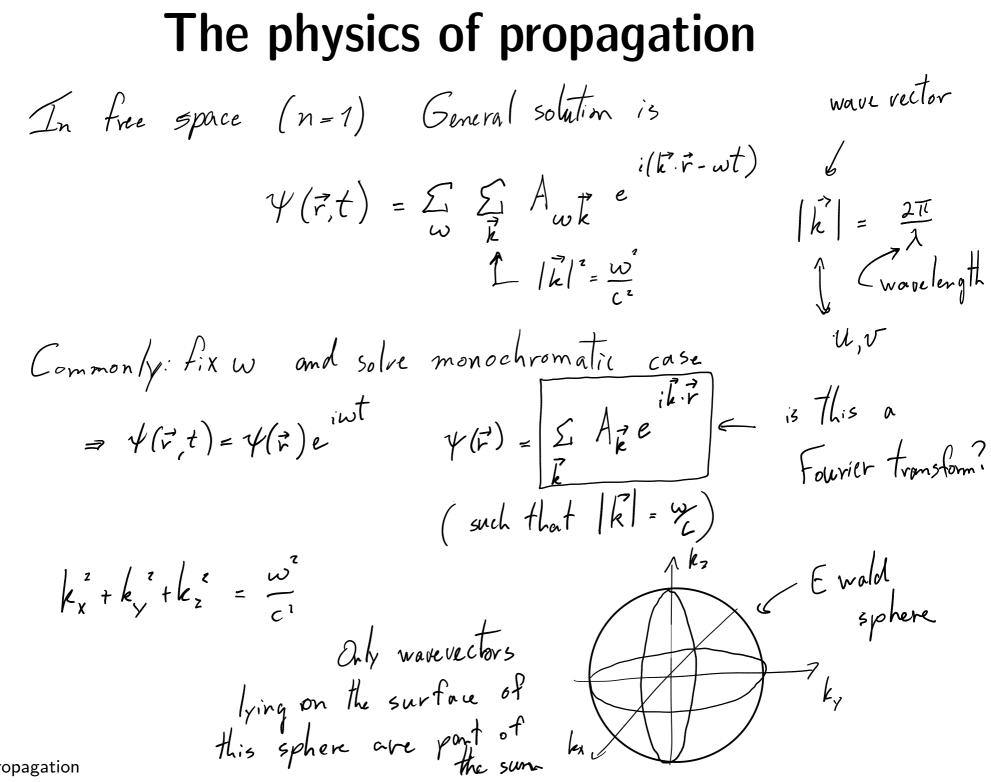


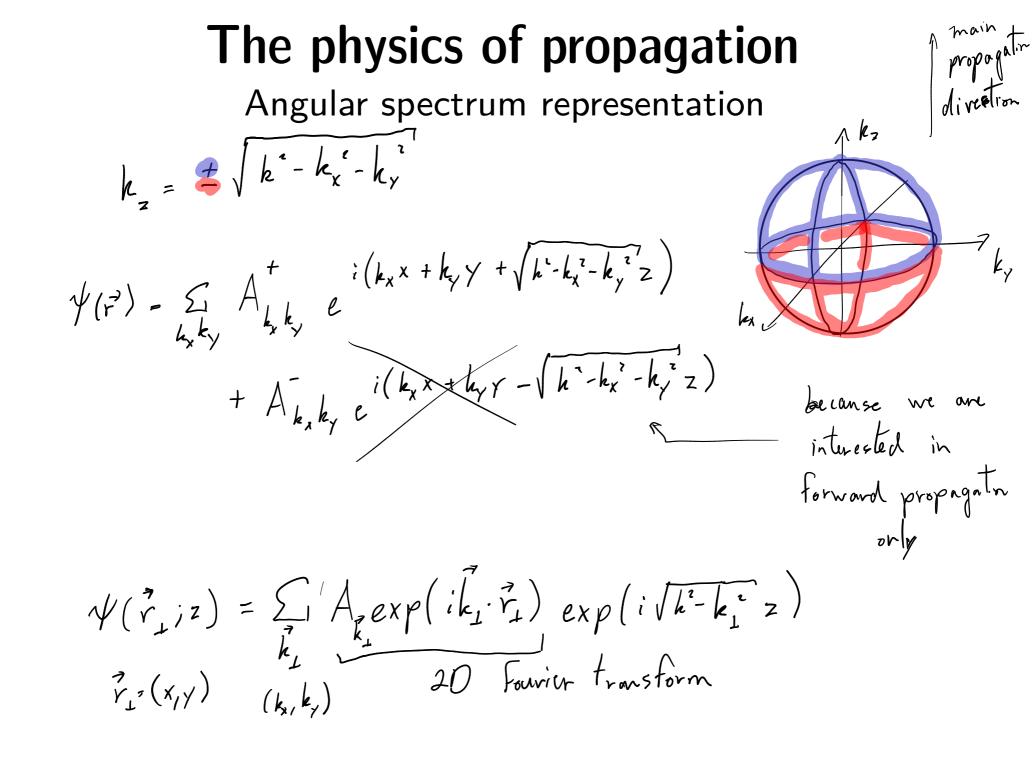
X-ray hologram



TEM through-focus series

sources: Mayo *et al.* Opt. Express (2003) http://www.christophtkoch.com/Vorlesung/





Forward propagation

$$z=0 \quad \forall (\vec{r}_{\perp}; z=0) = \underset{\vec{k}_{\perp}}{\leq} A_{\vec{k}_{\perp}} exp(i\vec{k}_{\perp} \cdot \vec{r}_{\perp})$$

$$\longrightarrow A_{\vec{k}_{\perp}} = \int \{\forall (\vec{r}_{\perp}; z=0)\}$$
Offin: $|\vec{k}_{\perp}| \ll k$ "paraxial approximation"
 $\sqrt{k^{*}-k_{\perp}^{*}} = k\sqrt{1-\frac{k_{\perp}^{*}}{k^{*}}} \simeq k(1-\frac{k_{\perp}^{*}}{2k^{*}})$

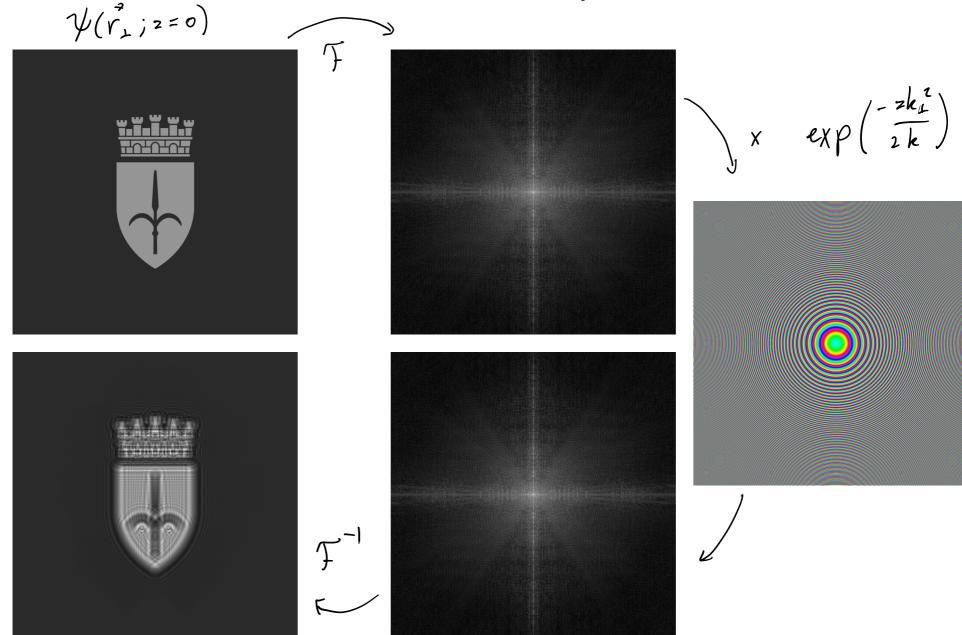
$$= k-\frac{k_{\perp}^{*}}{2k}$$
(small angle diffraction)
 $exp(i\sqrt{k^{*}-k_{\perp}^{*}}z) \simeq exp(ik_{\perp}) exp(-\frac{izk_{\perp}^{*}}{2k})$
of a sphere
"Fresnel propagator"

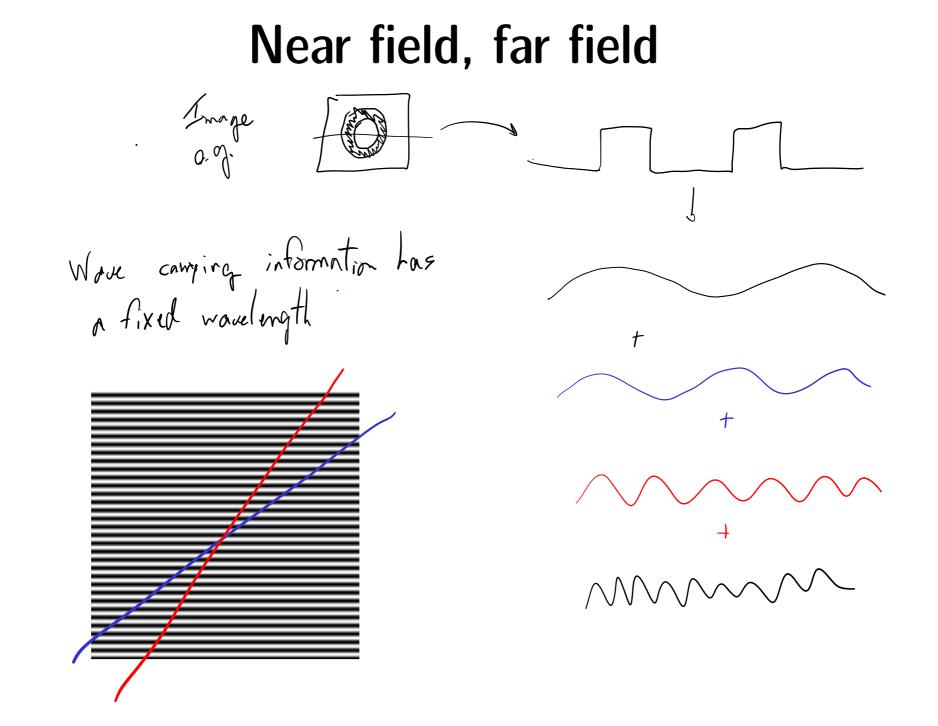
Forward propagation

$$\begin{aligned}
\psi(\vec{r}_{\perp j} z) &= \int^{-1} \left\{ \int \left\{ \psi(r_{\perp j} z = 0) \right\}^{2} exp\left(-\pi i \lambda z \tilde{u}^{2} \right) \right\} \\
\overset{"}{=} \sqrt{r_{i}ck} \overset{"}{=} \frac{1}{k!} \quad F.T. \quad e^{i\vec{k}\cdot\vec{r}} \quad \Rightarrow e^{i\vec{k}\cdot\vec{r}} \\
& i\vec{k}_{\perp} z = (\lambda\pi u)^{2} = 4\pi^{2}u^{2} \\
\frac{\pi}{2k} z = \frac{\pi}{4\pi}
\end{aligned}$$
Trick $\overset{"}{=} \frac{1}{k!} \quad F.T. \quad e^{i\vec{k}\cdot\vec{r}} \quad \Rightarrow e^{i\vec{k}\cdot\vec{r}} \\
& u.x = n\cdot m_{N} \\
& u.x = n\cdot u. \\
& u.x = n\cdot m_{N} \\
& u.$

Forward propagation

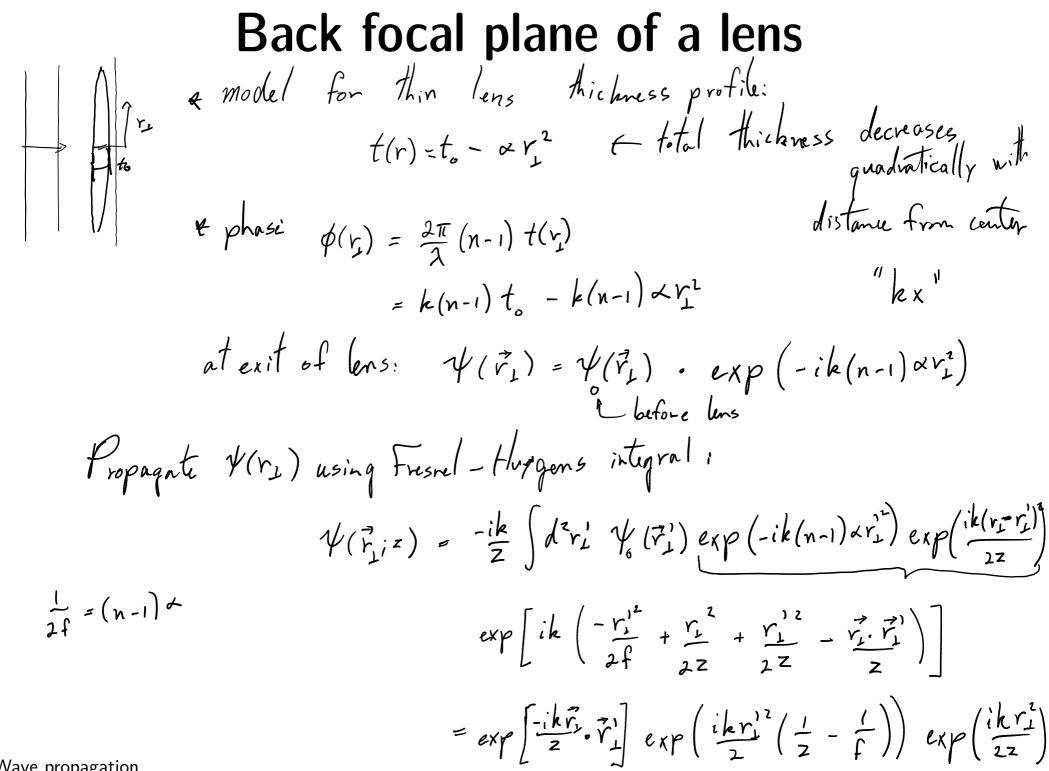
A numerical recipe





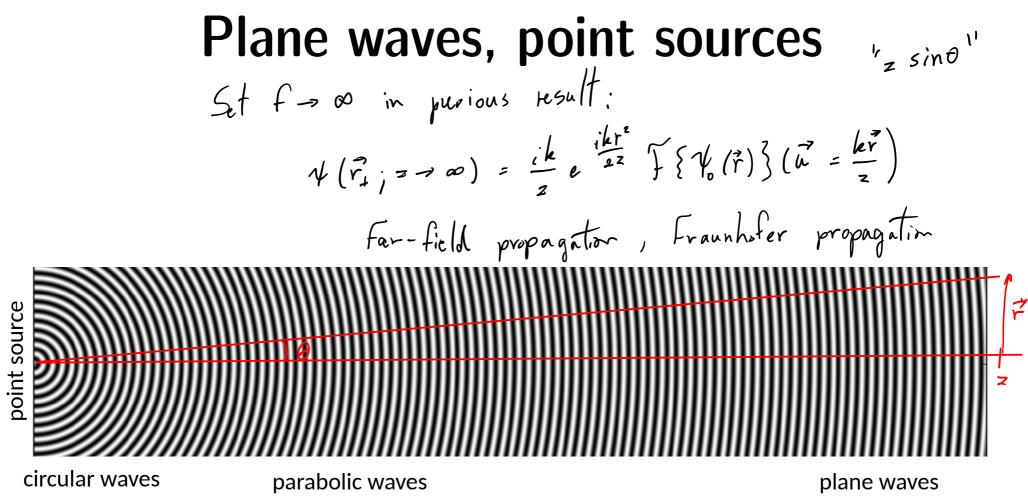
Near field, far field

$$\begin{aligned}
\mu(r_{\perp};z) &= \int^{-1} \left\{ \int \left\{ \Psi(r_{\perp};z=o) \right\} \exp\left(\frac{-izh_{\perp}^{2}}{2k}\right) \right\} \\
&= \left\{ \Psi(r_{\perp};z=o) \right\} \times \left\{ P_{z}\left(\vec{r}_{\perp}\right) \right\} \\
&= \left\{ \Psi(r_{\perp};z=o) \right\} \times \left\{ P_{z}\left(\vec{r}_{\perp}\right) \right\} \\
&= \frac{1}{2\pi i} \exp\left(-\pi i \lambda_{z} \frac{\pi}{u}\right) \right\} \\
&= \frac{1}{2\pi i} \exp\left(\frac{ikr_{\perp}^{2}}{2z}\right) \\
&= \frac{-i\partial\pi}{\lambda_{z}} \int d^{2}r_{\perp}^{2} \Psi(\vec{r}_{\perp};z=o) \exp\left(\frac{ik(r_{\perp}^{2}-r_{\perp}^{2})^{2}}{2z}\right) \\
&= Fresnel - Hurgens integral^{11}
\end{aligned}$$



Back focal plane of a lens

$$\begin{aligned}
& \Psi(\vec{r}_{\perp};z) = -\frac{ik}{2} \exp\left(\frac{ikr_{\perp}^{2}}{2z}\right) \int \Psi_{0}(\vec{r}_{\perp}) \exp\left(-\frac{ikr_{\perp}^{2}}{2}\cdot\vec{r}_{\perp}^{2}\right) \\
& \cdot \exp\left(\frac{ikr_{\perp}^{2}}{2}(\frac{i}{2}-\frac{i}{f})\right) \\
& \cdot \exp\left(\frac{ikr_{\perp}^{2}}{2}(\frac{i}{2}-\frac{i}{f})\right) \\
& \Psi(\vec{r}_{\perp};z=f) = -\frac{ik}{2} \exp\left(\frac{ikr_{\perp}^{2}}{2z}\right) \int \{\Psi_{0}(r)\}(\vec{a}=kr^{2}) \\
& \Psi(\vec{r}_{\perp};z=f) = -\frac{ik}{2} \exp\left(\frac{ikr_{\perp}^{2}}{2z}\right) \int \{\Psi_{0}(r)\}(\vec{a}=kr^{2}) \\
& \text{A lens acts as a Fourier transform operator!} \\
& \text{"bock focal plane": plane where F.T. is present} \\
& \text{Grast Abbe imaging theory based on} \\
& \text{this realization}
\end{aligned}$$

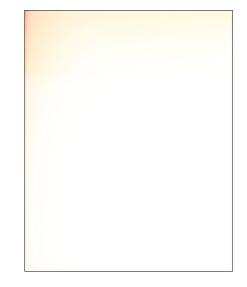


evanescent waves contact region

parabolic waves near field Fresnel region plane waves far field Fraunhofer region

Why optical elements?





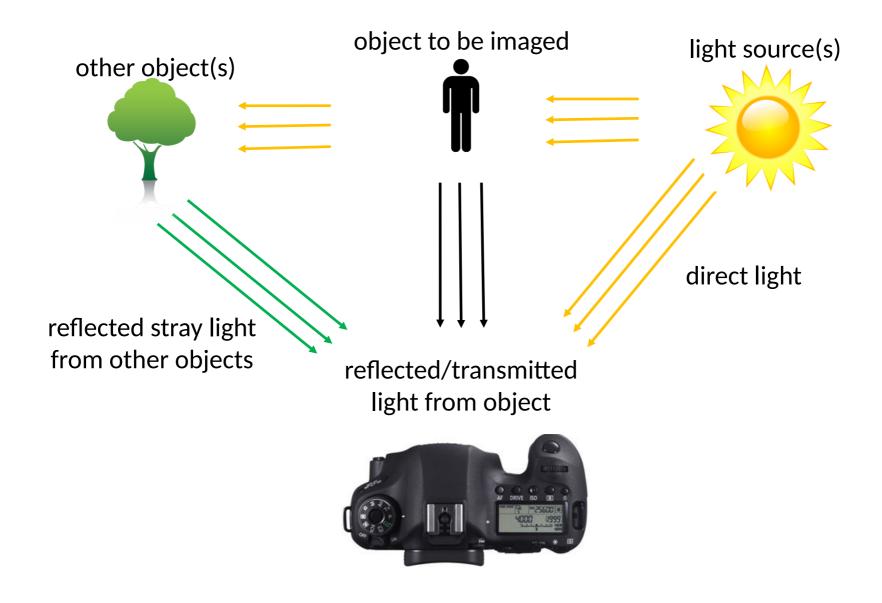
without objective lens

with objective lens



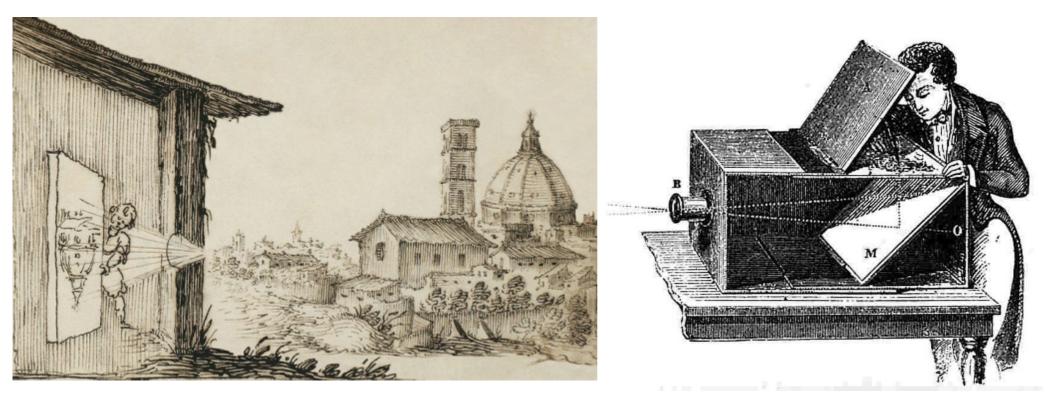
Why optical elements?

- Information from many sources overlaps in detector plane
- Need models to understand image forming systems



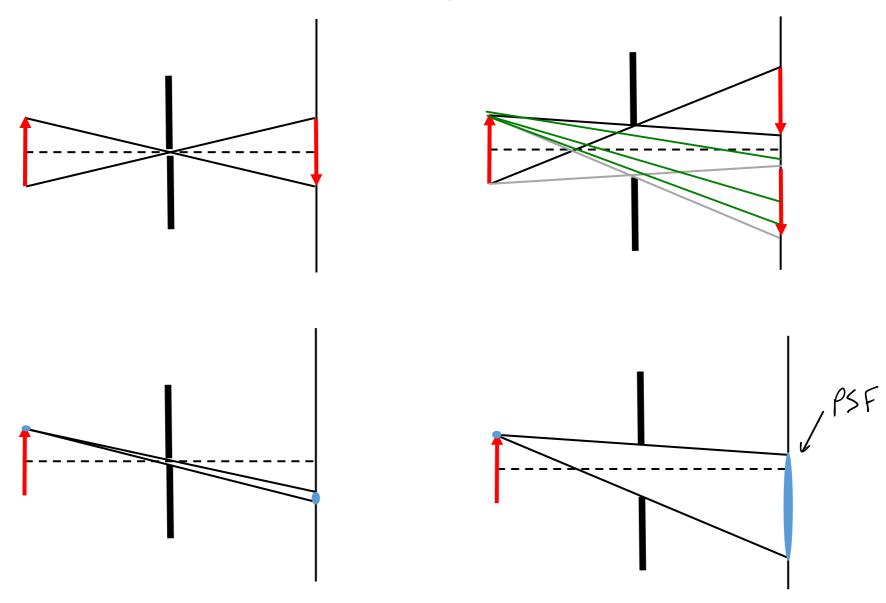
Pinhole camera model

camera obscura

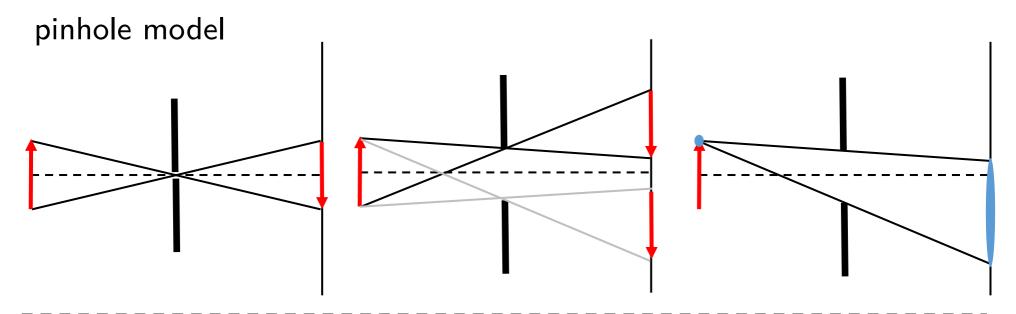


Pinhole camera model

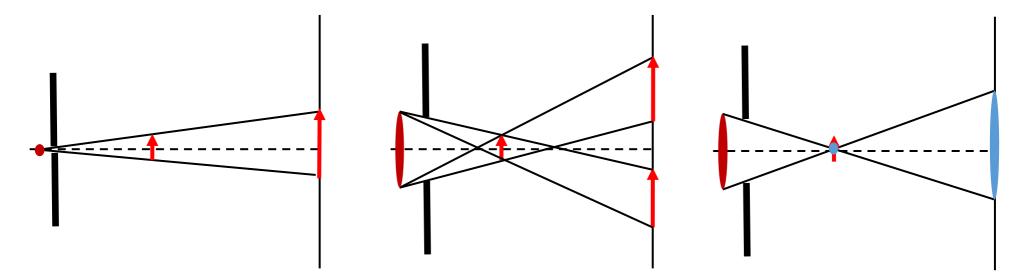
PSF determined by aperture width

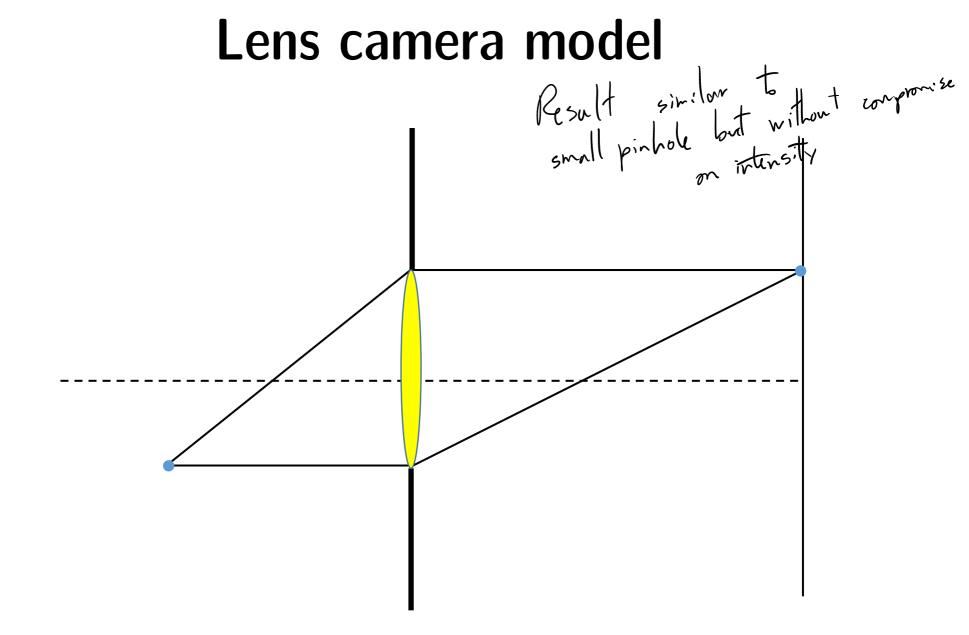


Projection model

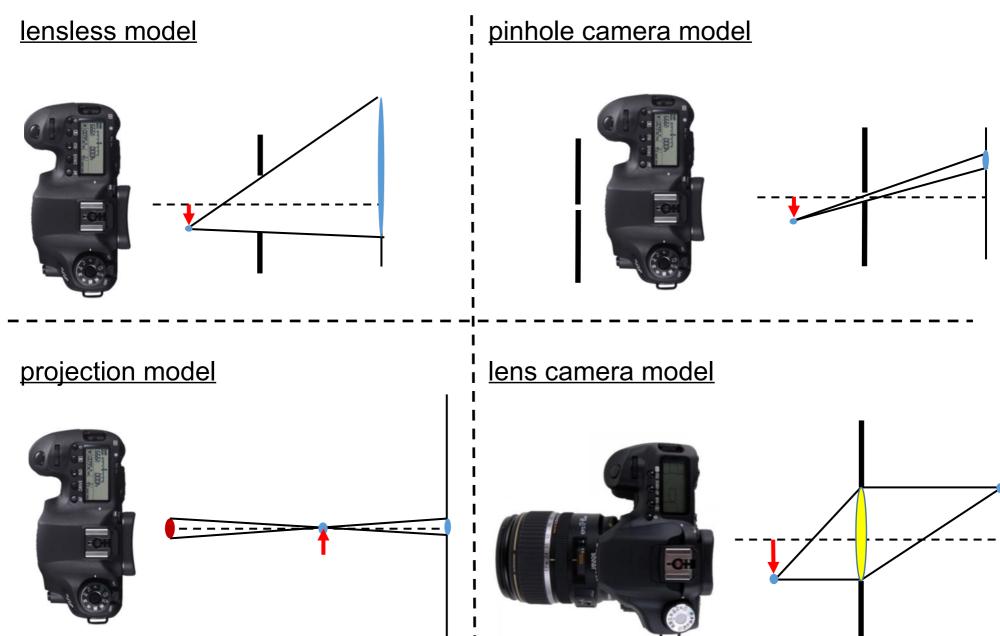


projection model





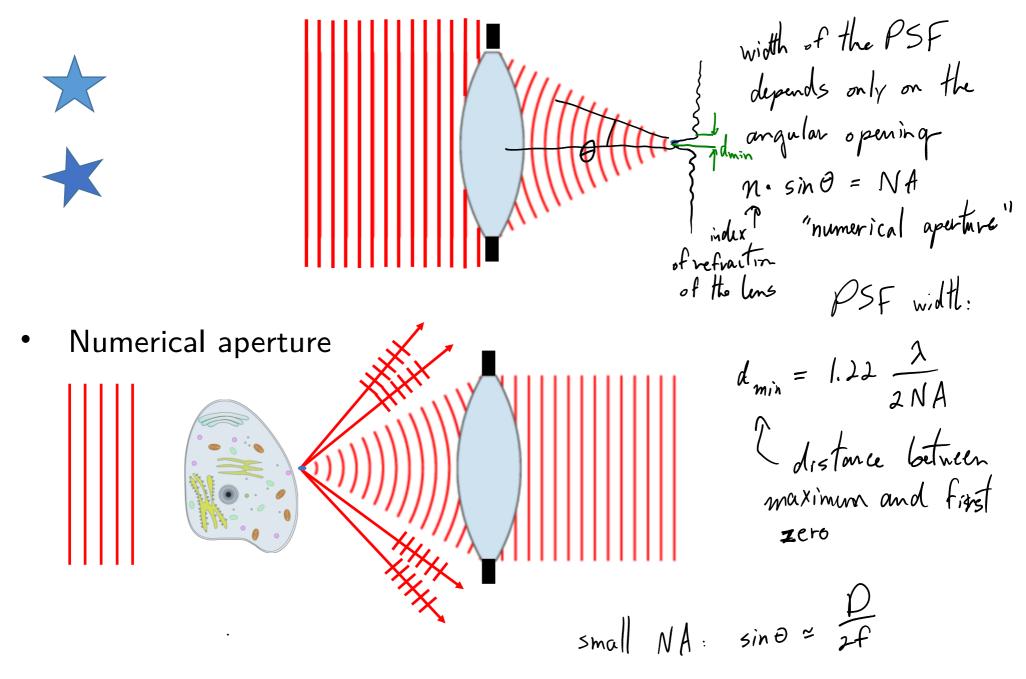
Lens camera model

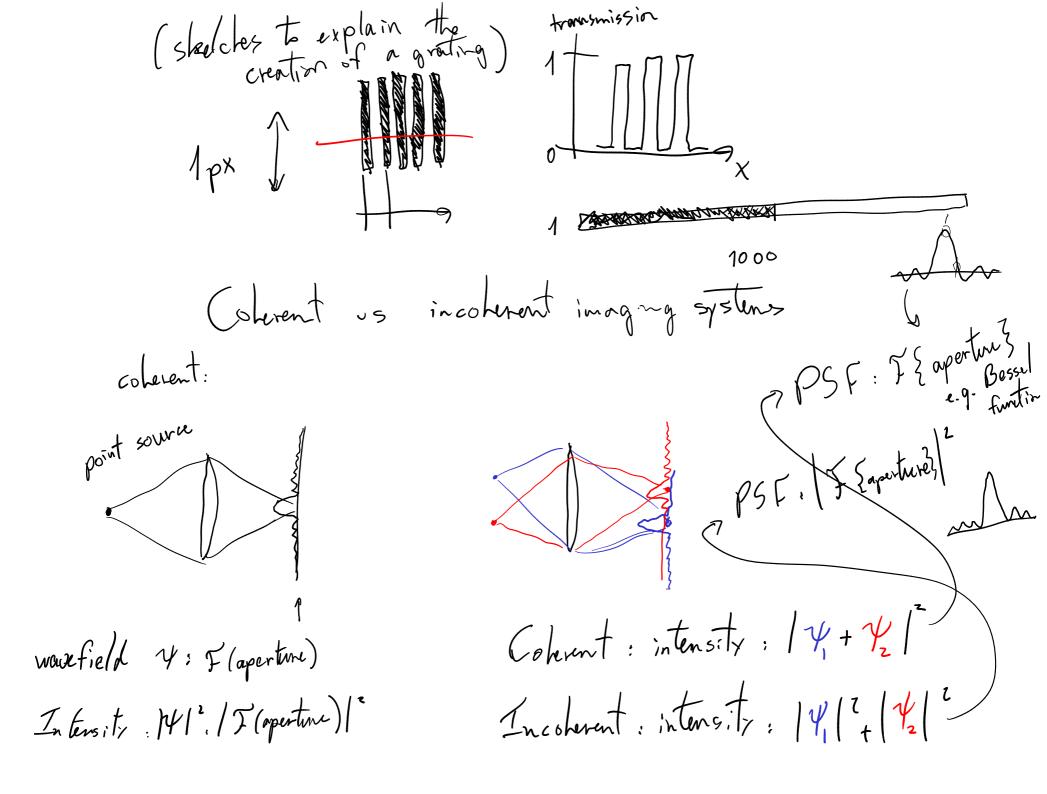


Diffraction-limited imaging systems

Rayleigh criterion

PSF: Airy "disc" Bessel function





Scanning systems

Transmission

- Scanning Transmission Electron Microscopy
- Scanning Transmission X-ray Microscopy

Indirect (reflection, scattering, fluorescence, ...)

- Laser Scanning Confocal Micropsopy
- Scanning Electron Microscopy
- X-ray Fluorescence Microscopy
- PhotoEmission Electron Microscopy

• ...

Physical probe

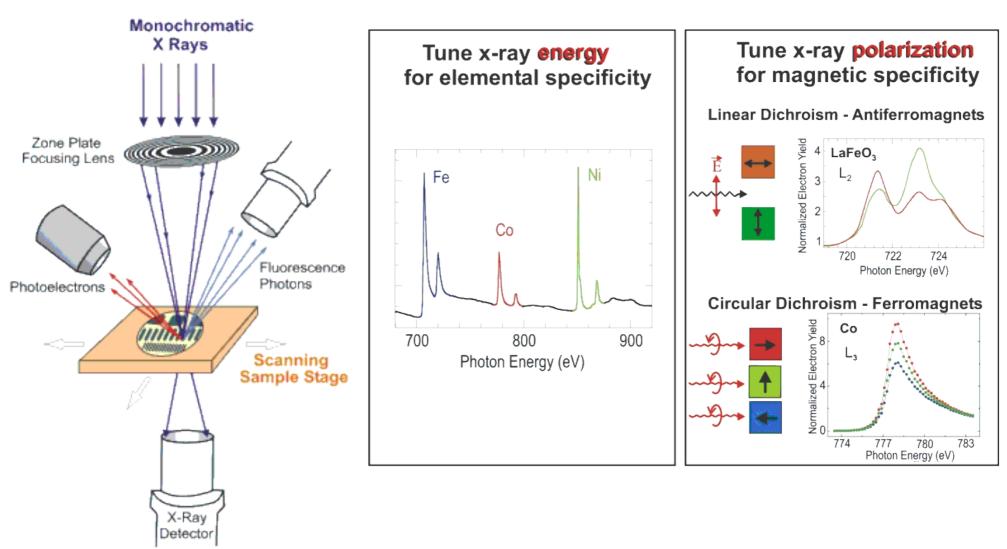
- Atomic Force Microscopy
- Scanning Tunneling Microscopy

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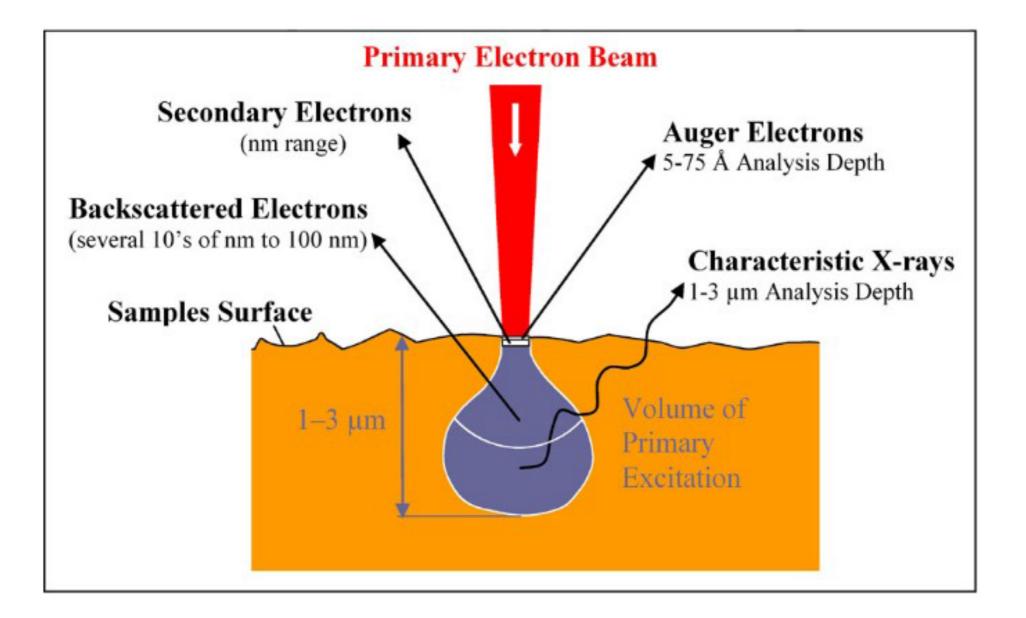
Scanning transmission X-ray microscopy

Scanning Transmission X-ray Microscopy

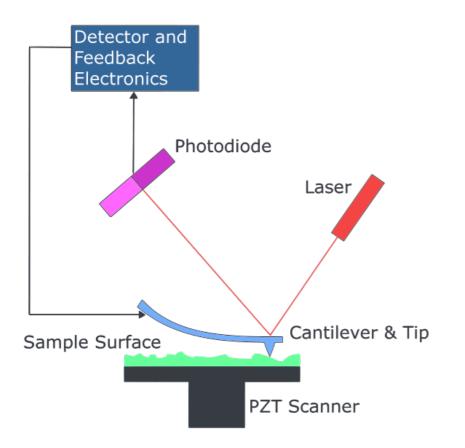
STXM

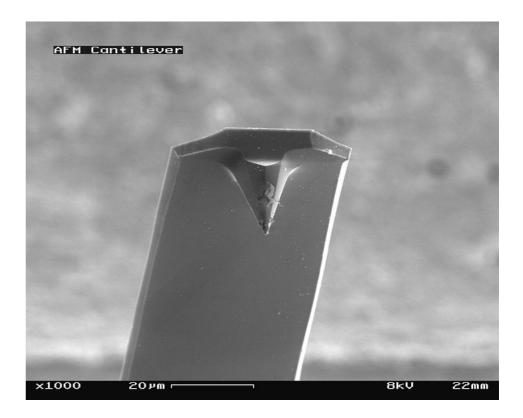


Scanning electron microscopy



Atomic force microscopy





Resolution in scanning systems

Resolution mainly limited by probe size

